Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/790,785	MITAMURA ET AL.	
Examiner	Art Unit	
Patrick J. Lee	2878	

SEARCHED				
Class	Subclass	Date	Examiner	
250	231.13, 231.14, 231.17, 237R	6/10/05 6/13/05 6/14/05	PL	
250	237G		PL	
341	13-14		PL	
33	1PT		PL	
356	614-616	1	PL	
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
	1				
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SEARCH (INCLUDING SEAF)
	DATE	EXMR
Consulted S. Allen	6/9/2005	PL
East (see attached)	6/10/2005	PL
East (see attached)	6/13/2005	PL
East (see attached)	6/14/2005	PL